## INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)

Docket Number (Optional)	Application Number	
TWI-24910	NEW	
Applicant(s)		
Alex Salnik et al.		
Filing Date	Group Art Unit	
HEREWITH	Unknown	

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
MAL	*AA	4,579,463	04/01/1986	Rosencwaig et al.	374	57	05/21/1984
1	*AB	4,634,290	01/06/1987	Rosencwaig et al.	374	5	11/14/1985
	*AC	4,636,088	01/13/1987	Rosencwaig et al.	374	5	05/21/1984
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REF	NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	YES	No
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## OTHER DOCUMENTS

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MAL	AH	J. Opsal et al., "Theory of the Temporal Behavior of Modulated Optical Reflectance in Silicon," Digest of 5th International Topical Meeting of Photoacoustic and Photothermal Phenomena (Heidelberg, Germany), July 27-30, 1987, pp. coversheet, 103-104.	
	Al	J. Opsal et al., "Temporal behavior of modulated optical reflectance in silicon," J. Appl. Phys., Vol. 61, No. 1, 1 January 1987), pp. 240-248.	
	AJ	A. Rosencwaig et al., "Temporal Behavior of Modulated Reflectance Signal in Silicon," from Review of Progress in Quantitative Nondestructive Evaluation, Rev. Progress in QNDE, Vol. 6A (1987), pp. 237-244.	
	AK	A. Rosencwaig et al., "Temporal Behavior of Modulated Optical Reflectance in Silicon," Abstract submitted for the March 1986 Meeting of the American Physical Society March 31-April 4, 1986, Bulletin of the American Physical Society 31(3), March 1986, p. 633.	
$\overline{V}$	AL	Excerpt: Therma-Probe 420 User Manual; Theory of Operation; Damage Relaxation (Decay Factor), 1 page in length. [See p. 3 of this Information Disclosure Statement for explanation]	
MAL	AM	In re U.S. Patent Application No. 10/387,259, filed March 12, 2003, entitled "Ion Implant Monitoring Through Measurement of Modulated Optical Response," by Alex Salnik et al., 17 pages in length.	

Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if	Examiner /Michael A. Lyons/ Date Considered 05/18/2006						
not in conformance and not considered. Include copy of this form with next communication to applicant.							